

Dialog DataStar

options

logout

feedback

help



databases

easy search

Advanced Search:**Inspec - 1898 to date (INZZ)**

limit

Search history:

No.	Database	Search term	Info added since	Results	
CP		[Clipboard]		0	-
1	INZZ	quiet ADJ steel	unrestricted	0	-

[hide](#) | [delete all search steps...](#) | [delete individual search steps...](#)
Enter your search term(s): [Search tips](#) ☐ Thesaurus mapping
 whole document


search

☐ Images

Click to select terms from the following list(s):

- Publication year 1950-
- Publication year 1898-1949
- Inspec thesaurus - enter a term
- Classification codes A: Physics, 0-1
- Classification codes A: Physics, 2-3
- Classification codes A: Physics, 4-5
- Classification codes A: Physics, 6
- Classification codes A: Physics, 7
- Classification codes A: Physics, 8
- Classification codes A: Physics, 9
- Classification codes B: Electrical & Electronics, 0-5
- Classification codes B: Electrical & Electronics, 6-9
- Classification codes C: Computer & Control
- Classification codes D: Information Technology
- Classification codes E: Mech., Manufac. & Production Engineering
- Treatment codes
- Inspec sub-file
- Language of publication

 Publication types

[Top](#) - [News & FAQs](#) - [Dialog](#)

© **2008** Dialog

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) | [Purchase History](#) | [Cart](#) | [Sitemap](#)

Welcome United States Patent and Trademark Office

[Search Session History](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)[SUPPORT](#)

Edit an existing query or
compose a new query in the
Search Query Display.

Thu, 22 May 2008, 9:40:21 PM EST

Search Query Display

Select a search number (#)
to:

- Add a query to the Search Query Display
- Combine search queries using AND, OR, or NOT
- Delete a search
- Run a search

Recent Search Queries

#1 ((quiet steel)<in>metadata)

#2 ((quiet steel)<in>metadata)

[Help](#) [Contact Us](#) [Privacy & Security](#)

© Copyright 2008 IEEE – All Rights

Indexed by
 Inspec®


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) | [Purchase History](#)

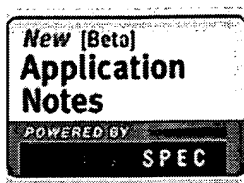
Welcome United States Patent and Trademark Office

[Search Results](#)
[BROWSE](#)
[SEARCH](#)
[IEEE XPLORE GUIDE](#)

Results for "gigapascal"

Your search matched 19 of 1701526 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.



» Search Options

[View Session History](#)
[New Search](#)

» Key

IEEE JNL IEEE Journal or Magazine

IET JNL IET Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IET CNF IET Conference Proceeding

IEEE STD IEEE Standard

Modify Search

gigapascal*

☐ Check to search only within this results set

 Display Format: ☒ Citation ☐ Citation & Abstract

IEEE/IET

Books

Educational Courses

A

IEEE/IET journals, transactions, letters, magazines, conference proceedings, and

- ☐ 1. **Notch Root Oxide Formation During Fatigue of Polycrystalline Silicon Si**
 Pierron, O. N.; Muhlstein, C. L.;
[Microelectromechanical Systems, Journal of](#)
 Volume 16, Issue 6, Dec. 2007 Page(s):1441 - 1450
 Digital Object Identifier 10.1109/JMEMS.2007.906076
[AbstractPlus](#) | Full Text: [PDF\(958 KB\)](#) IEEE JNL
[Rights and Permissions](#)
- ☐ 2. **Young's Modulus Measurements in Standard IC CMOS Processes Using**
 Marshall, J. C.; Herman, D. L.; Vernier, P. T.; DeVoe, D. L.; Gaitan, M.;
[Electron Device Letters, IEEE](#)
 Volume 28, Issue 11, Nov. 2007 Page(s):960 - 963
 Digital Object Identifier 10.1109/LED.2007.906460
[AbstractPlus](#) | Full Text: [PDF\(145 KB\)](#) IEEE JNL
[Rights and Permissions](#)
- ☐ 3. **Numerical Study of Gold Wire Bonding Process on Cu/Low-k Structures**
 Viswanath, A.G.K.; Xiaowu Zhang; Ganesh, V.P.; Lu Chun;
[Advanced Packaging, IEEE Transactions on \[see also Components, Packag](#)
[Technology, Part B: Advanced Packaging, IEEE Transactions on\]](#)
 Volume 30, Issue 3, Aug. 2007 Page(s):448 - 456
 Digital Object Identifier 10.1109/TADVP.2006.890213
[AbstractPlus](#) | Full Text: [PDF\(1584 KB\)](#) IEEE JNL
[Rights and Permissions](#)
- ☐ 4. **Arrays of High Tilt-Angle Micromirrors for Multiobject Spectroscopy**
 Waldis, S.; Zamkotsian, F.; Clerc, P.-A.; Noell, W.; Zickar, M.; de Rooij, N. de;
[Selected Topics in Quantum Electronics, IEEE Journal of](#)
 Volume 13, Issue 2, March-april 2007 Page(s):168 - 176
 Digital Object Identifier 10.1109/JSTQE.2007.894181
[AbstractPlus](#) | Full Text: [PDF\(522 KB\)](#) IEEE JNL
[Rights and Permissions](#)

Interaction of multichip module substrates with high-density connectors

- ☐ 5. Belopolsky, Y.;
Micro. IEEE
Volume 13, Issue 2, April 1993 Page(s):36 - 44
Digital Object Identifier 10.1109/40.207087
[AbstractPlus](#) | Full Text: [PDF](#)(564 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ 6. Turning heads
Bar-Cohen, Y.;
Spectrum, IEEE
Volume 41, Issue 6, June 2004 Page(s):28 - 33
Digital Object Identifier 10.1109/MSPEC.2004.1303370
[AbstractPlus](#) | Full Text: [PDF](#)(4845 KB) | Full Text: [HTML](#) IEEE JNL
[Rights and Permissions](#)

- ☐ 7. Dielectrophoretic assembly of carbon nanofiber nanoelectromechanical
Evoy, S.; Riegelman, M.A.; Naguib, N.; Haihui Ye; Jaroenapibal, P.; Luzzi, D.;
Nanotechnology, IEEE Transactions on
Volume 4, Issue 5, Sept. 2005 Page(s):570 - 575
Digital Object Identifier 10.1109/TNANO.2005.851404
[AbstractPlus](#) | Full Text: [PDF](#)(1400 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ 8. High-modulus low-linear-expansion-coefficient loose-jacket optical fiber
Yamamoto, F.; Shuto, Y.; Itoh, H.; Yamakawa, S.;
Lightwave Technology, Journal of
Volume 2, Issue 2, Apr 1984 Page(s):83 - 87
[AbstractPlus](#) | Full Text: [PDF](#)(1512 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ 9. The submarine optical cable of the SUBMARCOM S 280 system
Trezeguet, J.-P.; Ollion, P.; Franco, P.; Thiennot, J.;
Lightwave Technology, Journal of
Volume 2, Issue 6, Dec 1984 Page(s):846 - 855
[AbstractPlus](#) | Full Text: [PDF](#)(2856 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ 10. The Submarine Optical Cable of the Submarcom S 280 System
Trezeguet, J.; Ollion, P.; Franco, P.; Thiennot, J.;
Selected Areas in Communications, IEEE Journal on
Volume 2, Issue 6, Nov 1984 Page(s):886 - 895
[AbstractPlus](#) | Full Text: [PDF](#)(896 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ 11. Mechanical stress as a function of temperature in aluminum films
Gardner, D.S.; Flinn, P.A.;
Electron Devices, IEEE Transactions on
Volume 35, Issue 12, Dec 1988 Page(s):2160 - 2169
Digital Object Identifier 10.1109/16.8790
[AbstractPlus](#) | Full Text: [PDF](#)(1124 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ 12. Fabricating composite materials-a comprehensive problem-solving arch
tasks
Sticklen, J.; Kamel, A.; Hawley, M.; Adegbite, V.;
Expert, IEEE [see also IEEE Intelligent Systems and Their Applications]
Volume 7, Issue 2, April 1992 Page(s):43 - 53
Digital Object Identifier 10.1109/64.129282
[AbstractPlus](#) | Full Text: [PDF](#)(2352 KB) IEEE JNL

[Rights and Permissions](#)

- ☐ **13. The evolution of a decision support architecture for polymer composite:**
Lenz, T.J.; McDowell, J.K.; Hawley, M.C.; Kamel, A.; Sticklen, J.;
[Expert, IEEE \[see also IEEE Intelligent Systems and Their Applications\]](#)
Volume 11, Issue 5, Oct. 1996 Page(s):77 - 83
Digital Object Identifier 10.1109/64.539020
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(2636 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ **14. Scanning tunneling microscopy of DNA**
Dunlop, D.;
[Engineering in Medicine and Biology Magazine, IEEE](#)
Volume 15, Issue 1, Jan.-Feb. 1996 Page(s):46 - 50
Digital Object Identifier 10.1109/51.482794
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(848 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ **15. Mechanical properties of thin films from the load deflection of long clam**
Ziebart, V.; Paul, O.; Munch, U.; Schwizer, J.; Baltes, H.;
[Microelectromechanical Systems, Journal of](#)
Volume 7, Issue 3, Sept. 1998 Page(s):320 - 328
Digital Object Identifier 10.1109/84.709651
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(300 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ **16. Large-scale atomistic simulations of dynamic fracture**
Vashishta, P.; Kalia, R.K.; Nakano, A.;
[Computing in Science & Engineering \[see also IEEE Computational Science\]](#)
Volume 1, Issue 5, Sept.-Oct. 1999 Page(s):56 - 65
Digital Object Identifier 10.1109/5992.790588
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(1636 KB) IEEE JNL
[Rights and Permissions](#)

- ☐ **17. Experimental methods with flux-compression generators**
Novac, B.M.; Smith, I.R.; Stewardson, H.R.; Senior, P.;
[Engineering Science and Education Journal](#)
Volume 5, Issue 5, Oct. 1996 Page(s):211 - 222
[AbstractPlus](#) | Full Text: [PDF](#)(2248 KB) IET JNL

- ☐ **18. A finite element study of process induced stress in the transistor channel contact and gate stack [MOSFET]**
Torregiani, C.; Liu, J.; Vandeveld, B.; Degryse, D.; Van Dal, M.J.; Benedetti,
[Thermal and Mechanical Simulation and Experiments in Microelectronics and EuroSimE 2004. Proceedings of the 5th International Conference on](#)
2004 Page(s):61 - 68
Digital Object Identifier 10.1109/ESIME.2004.1304023
[AbstractPlus](#) | Full Text: [PDF](#)(1190 KB) IEEE CNF
[Rights and Permissions](#)

- ☐ **19. The installation for pulse compression with use of the heavy current pul**
Fridman, B.E.; Rutberg, Ph.G.;
[Pulsed Power Conference, 1997. Digest of Technical Papers. 1997 11th IEEE](#)
Volume 2, 29 June-2 July 1997 Page(s):1411 - 1416 vol.2
Digital Object Identifier 10.1109/PPC.1997.674600
[AbstractPlus](#) | Full Text: [PDF](#)(628 KB) IEEE CNF
[Rights and Permissions](#)



[Help](#) [Contact Us](#)

© Copyright 20